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MOS FET

FK8V03060L

Panasonic

FK8V03060L

Silicon N-channel MOS FET

For lithium-ion secondary battery protection circuit For DC-DC Converter

■ Features

- Low drain-source On-state Resistance RDS(on) typ. = 22 m Ω (VGS = 4.5 V)
- High-speed switching : Qg = 3.8 nC
- Halogen-free / RoHS compliant (EU RoHS / UL-94 V-0 / MSL:Level 1 compliant)

■ Absolute Maximum Ratings Ta = 25 °C

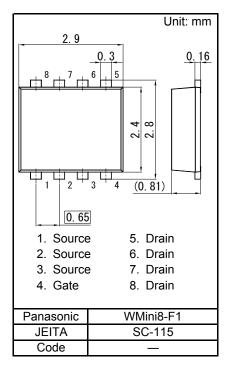
■ Marking Symbol: 3F

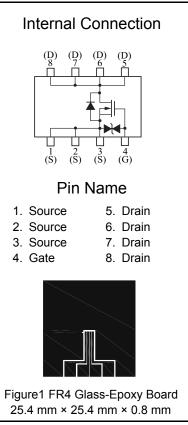
■ Packaging

Embossed type (Thermo-compression sealing): 3 000 pcs / reel (standard)

Parameter	Symbol	Rating	Unit	
Drain-source Voltage	VDS	33	V	
Gate-source Voltage	VGS	±20	V	
Drain Current (Steady State) *1	ID	6.5		
Drain Current (t = 10 s) ^{*1}	טו	8		
Drain Current (Pulsed) *1,*2	IDp	26	Α	
Source Current (Pulsed)	ISp	6.5		
(Body Diode) *1,*2	(BD)	0.5		
Total Power Dissipation (Steady State) *1	PD	1	W	
Total Power Dissipation (t = 10 s) *1	FD	1.5	٧٧	
Channel Temperature	Tch	150	°C	
Operating Ambient Temperature	Topr	-40 to +85	°C	
Storage Temperature Range	Tstg	-55 to +150	°C	

Note) *1 Device mounted on a glass-epoxy board (See Figure 1)





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^{*2} Pulse test: Ensure that the channel temperature does not exceed 150°C

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■ Electrical Characteristics Ta = 25°C ± 3°C

Static Characteristics

Parameter	Symbol	Conditions	Min	Тур	Max	Unit
Drain-source Breakdown Voltage	VDSS	ID = 1 mA, VGS = 0 V	33			V
Zero Gate Voltage Drain Current	IDSS	VDS = 33 V, VGS = 0 V			10	μΑ
Gate-source Leakage Current	IGSS	VGS = ± 16 V, VDS = 0 V			±10	μΑ
Gate-source Threshold Voltage	Vth	ID = 0.48 mA, VDS = 10 V	1		2.5	V
Drain cource On state Desistance '	RDS(on)1	ID = 3.3 A, VGS = 10 V		15	20	m()
	RDS(on)2	ID = 3.3 A. VGS = 4.5 V		22	35	mΩ

Dynamic Characteristics

Input Capacitance	Ciss	VDS = 10 V VCS = 0 V	360	
Output Capacitance	Coss	VDS = 10 V, VGS = 0 V f = 1 MHz	70	pF
Reverse Transfer Capacitance	Crss	1 - 1 1011 12	50	
Turn-on Delay Time *2	td(on)	VDD = 15 V, VGS = 0 to 10 V	8	
Rise Time *2	tr	ID = 3.3 A	3	ns
Turn-off Delay Time *2	td(off)	VDD = 15 V, VGS = 10 to 0 V	24	115
Fall Time *2	tf	ID = 3.3 A	9	
Total Gate Charge	Qg	VDD = 15 V. VGS = 0 to 4.5 V.	3.8	
Gate-source Charge	Qgs	ID = 6.5 A	1.4	nC
Gate-drain Charge	Qgd	1D - 0.0 A	1.6	

Body Diode Characteristic					
Diode Forward Voltage *1	VSD	IS = 3.3 A, VGS = 0 V	0.8	1.2	V

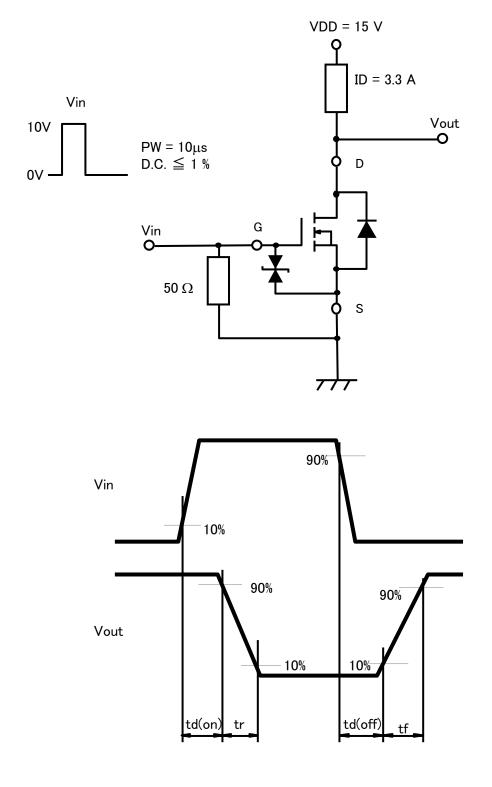
Note) 1. Measuring methods are based on JAPANESE INDUSTRIAL STANDARD JIS C 7030 Measuring methods for transistors.

^{2. *1} Pulse test: Ensure that the channel temperature does not exceed 150°C

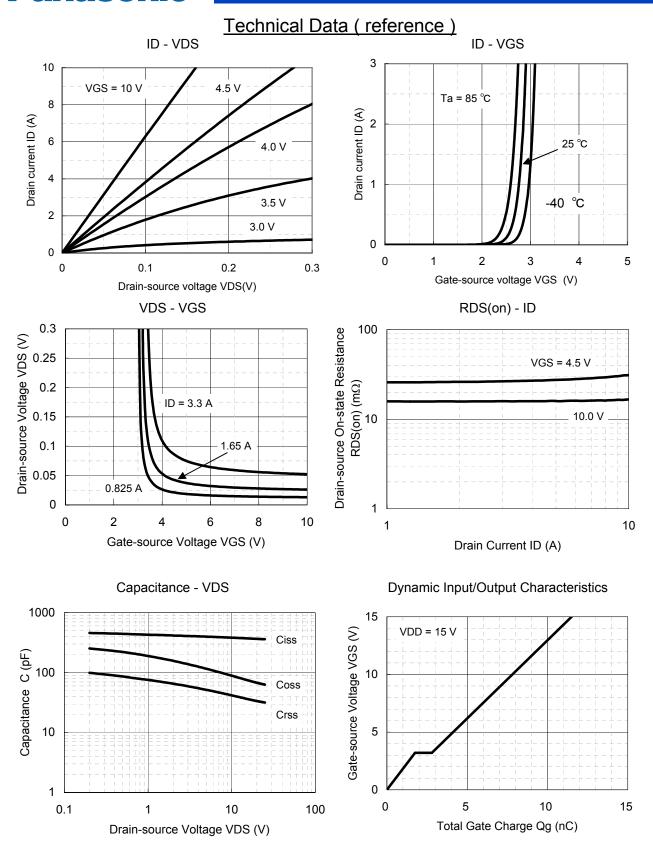
^{*2} Measurement circuit for Turn-on Delay Time/Rise Time/Turn-off Delay Time/Fall Time

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*2 Measurement circuit for Turn-on Delay Time/Rise Time/Turn-off Delay Time/Fall Time



Panasonic FK8V03060L



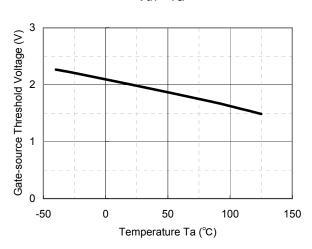
MOS FET

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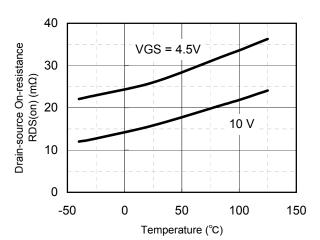
MOS FET FK8V03060L

Technical Data (reference)

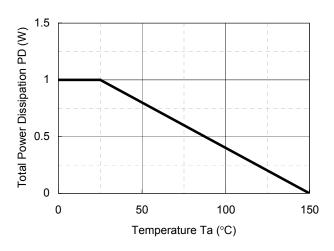
Vth - Ta



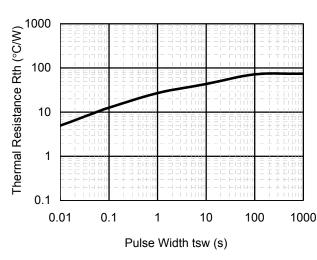
RDS(on) - Ta



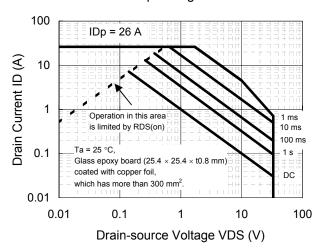
PD - Ta



Rth - tsw



Safe Operating Area

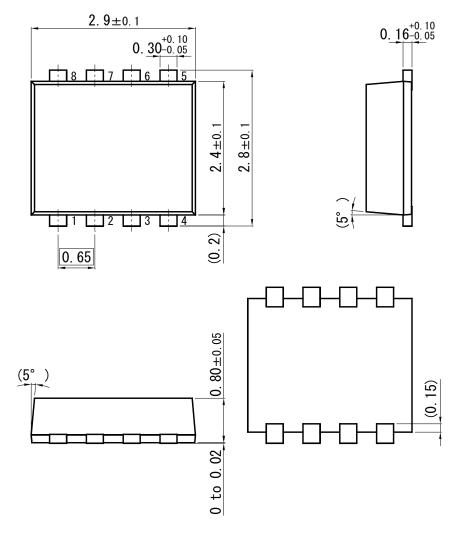


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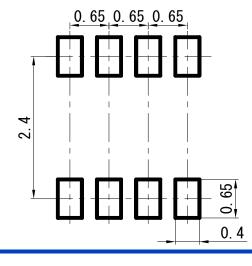
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WMini8-F1

Unit: mm



■ Land Pattern (Reference) (Unit : mm)



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